TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

# TC74ACT299P,TC74ACT299F

#### 8-Bit PIPO Shift Register with Asynchronous Clear

The TC74ACT299 is an advanced high speed CMOS 8-BIT PIPO SHIFT REGISTER fabricated with silicon gate and double-layer metal wiring C<sup>2</sup>MOS technology.

It achieves the high speed operation similar to equivalent Bipolar Schottky TTL while maintaining the CMOS low power dissipation.

This device may be used as a level converter for interfacing TLL or NMOS to High Speed CMOS. The inputs are compatible with TTL, NMOS and CMOS output voltage levels.

It has a four modes (HOLD, SHIFT LEFT, SHIFT RIGHT and LOAD DATA) controlled by the two selection inputs (S0, S1).

When one or both enable  $(\overline{G1}, \overline{G2})$  are high, the eight I/O outputs are forced to the high-impedance state; however, sequential operation or clearing of the register is not affected.

All inputs are equipped with protection circuits against static discharge or transient excess voltage.

#### Features (Note 1)(Note 2)

- High speed:  $f_{max} = 130 \text{ MHz}$  (typ.) at  $V_{CC} = 5 \text{ V}$
- Low power dissipation:  $I_{CC} = 8 \mu A (max)$  at  $Ta = 25^{\circ}C$
- Compatible with TTL outputs:  $V_{IL} = 0.8 V (max)$

 $V_{IH} = 2.0 V (min)$ 

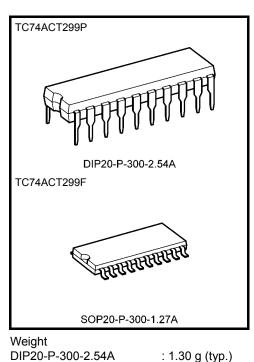
- Symmetrical output impedance:  $|I_{OH}| = I_{OL} = 24$  mA (min) Capability of driving 50  $\Omega$ transmission lines.
- Balanced propagation delays:  $t_{pLH} \simeq t_{pHL}$
- Pin and function compatible with 74F299

Note 1: Do not apply a signal to any bus terminal when it is in the output mode. Damage may result.

Note 2: All floating (high impedance) bus terminals must have their input levels fixed by means of pull up or pull down resistors.

#### **Pin Assignment**

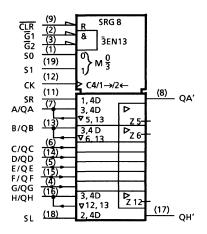
S0 G1 G2 G/QG E/QE C/QC A/QA QA' CLR GND	6 7 8 9		19 18 17 16	V <sub>cc</sub> S1 SL H/QH F/QF D/QD B/QB CK SR
		(TOP	VIEW)	



DIP20-P-300-2.54A SOP20-P-300-1.27A

: 1.30 g (typ.) : 0.22 g (typ.)

#### **IEC Logic Symbol**



### Truth Table

		Inputs								Inputs/ Outputs		puts
Mode	Select			Outputs Control		СК	Serial		A/O A			0.1
		CK	SL	SR	A/QA	H/QH	QA'	QH'				
Z	L	Н	Н	Х	Х	Х	Х	х	Z	Z	L	L
Clear	L	L	Х	L	L	Х	Х	Х	L	L	L	L
Clear	L	х	L	L	L	х	Х	х	L	L	L	L
Hold	Н	L	L	L	L	Х	Х	х	QA0	QH0	QA0	QH0
Shift	Н	L	Н	L	L		Х	Н	Н	QGn	Н	QGn
Right	Н	L	Н	L	L		х	L	L	QGn	L	QGn
Shift	Н	Н	L	L	L		Н	х	QBn	Н	QBn	Н
Left	Н	Н	L	L	L		L	х	QBn	L	QBn	L
Load	Н	Н	Н	Х	Х		Х	Х	а	h	а	h

Note: When one or both output controls are high, the eight input/output terminals are in the high-impedance state; however sequential or clearing of the register is not affected.

Z: High impedance

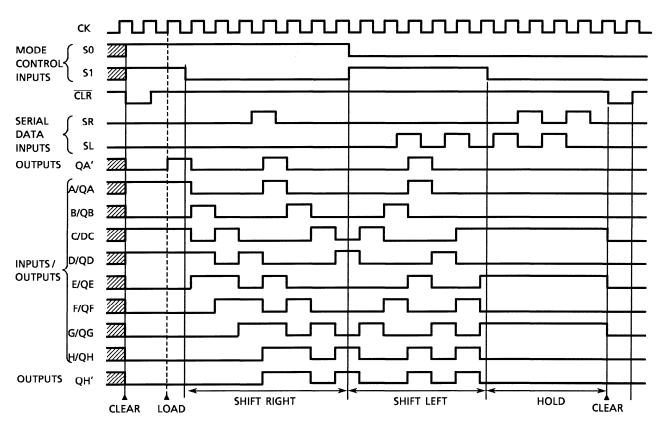
Qn0: The level of Qn before the indicated steady-state input conditions were established.

Qnn: The level of Qn before the most recent active transition indicated by  $\downarrow$  or  $\uparrow$ .

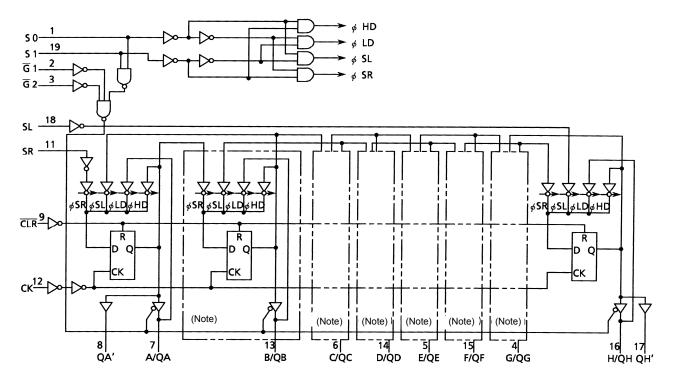
a, h: The level of the steady-state inputs A, H, respectively.

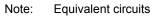
X: Don't care

#### **Timing Chart**



#### System Diagram





### Absolute Maximum Ratings (Note 1)

Characteristics	Symbol	Rating	Unit
Supply voltage range	V <sub>CC</sub>	–0.5 to 7.0	V
DC input voltage	V <sub>IN</sub>	-0.5 to V <sub>CC</sub> + 0.5	V
DC output voltage	V <sub>OUT</sub>	-0.5 to V <sub>CC</sub> + 0.5	V
Input diode current	I <sub>IK</sub>	±20	mA
Output diode current	IOK	±50	mA
DC output current	IOUT	±50	mA
DC V <sub>CC</sub> /ground current	ICC	±250	mA
Power dissipation	PD	500 (DIP) (Note 2)/180 (SOP)	mW
Storage temperature	T <sub>stg</sub>	–65 to 150	°C

Note 1: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 2: 500 mW in the range of Ta = -40 to  $65^{\circ}$ C. From Ta = 65 to  $85^{\circ}$ C a derating factor of -10 mW/°C should be applied up to 300 mW.

Characteristics	Symbol	Rating	Unit
Supply voltage	V <sub>CC</sub>	4.5 to 5.5	V
Input voltage	V <sub>IN</sub>	0 to V <sub>CC</sub>	V
Output voltage	V <sub>OUT</sub>	0 to V <sub>CC</sub>	V
Operating temperature	T <sub>opr</sub>	-40 to 85	°C
Input rise and fall time	dt/dV	0 to 10	ns/V

#### **Operating Ranges (Note)**

Note: The operating ranges must be maintained to ensure the normal operation of the device. Unused inputs must be tied to either VCC or GND.

### **Electrical Characteristics**

#### **DC Characteristics**

Characteristics	Symbol		Test Condition			-	Ta = 25°C	)	Ta = -40 to 85°C		Unit	
Characteriolico			V <sub>C</sub> (V			Min	Тур.	Max	Min	Max		
High-level input voltage	V <sub>IH</sub>		_			2.0	_		2.0	_	V	
Low-level input voltage	VIL		_			_	_	0.8	_	0.8	V	
		VIN	I <sub>OH</sub> = -50 μA		4.5	4.4	4.5	_	4.4	_		
High-level output voltage	V <sub>OH</sub>	= V <sub>IN</sub> V <sub>IL</sub>	I <sub>OH</sub> = -24 mA		4.5	3.94	—	—	3.80	—	V	
5			I <sub>OH</sub> = -75 mA	(Note)	5.5	—	—	—	3.85	—		
	V <sub>OL</sub>	V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>	$I_{OL} = 50 \ \mu A$		4.5	—	0.0	0.1	—	0.1		
Low-level output voltage			I <sub>OL</sub> = 24 mA		4.5	—	—	0.36	—	0.44	V	
5			I <sub>OL</sub> = 75 mA	(Note)	5.5				—	1.65		
3-state output off-state current	I <sub>OZ</sub>		$V_{IN} = V_{IH}$ or $V_{IL}$ $V_{OUT} = V_{CC}$ or GND		5.5	_	_	±0.5	_	±5.0	μΑ	
Input leakage current	I <sub>IN</sub>	$V_{IN} = V_C$	$V_{IN} = V_{CC}$ or GND		5.5	_	_	±0.1	_	±1.0	μA	
	ICC	$V_{IN} = V_C$	$V_{IN} = V_{CC}$ or GND			—	_	8.0	_	80.0	μA	
Quiescent supply current	IC		Per input: $V_{IN} = 3.4 V$ Other input: $V_{CC}$ or GND		5.5	_	_	1.35	_	1.5	mA	

Note: This spec indicates the capability of driving 50  $\Omega$  transmission lines.

One output should be tested at a time for a 10 ms maximum duration.

#### Timing Requirements (input: $t_r = t_f = 3 \text{ ns}$ )

Characteristics	Symbol	Test Condition	Test Condition			Ta = 40 to 85°C	Unit	
			V <sub>CC</sub> (V)	Typ. Limit		Limit		
Minimum pulse width	t <sub>W (L)</sub>		5.0 ± 0.5		5.0	5.0	ns	
(CK)	t <sub>W (H)</sub>		5.0 ± 0.5		5.0	5.0	115	
Minimum pulse width ( $\overline{\text{CLR}}$ )	<sup>t</sup> W (L)	_	$5.0\pm0.5$	_	5.0	5.0	ns	
Minimum set-up time (SL, SR, A~H)	ts	_	$5.0\pm0.5$	_	3.5	3.5	ns	
Minimum set-up time (S0, S1)	ts	_	$5.0\pm0.5$	_	6.0	6.5	ns	
Minimum hold time (SL, SR, A~H)	t <sub>h</sub>	_	$5.0\pm0.5$		2.0	2.0	ns	
Minimum hold time (S0, S1)	t <sub>h</sub>	_	$5.0\pm0.5$		0.0	0.0	ns	
Minimum removal time ( CLR )	t <sub>rem</sub>	_	$5.0\pm0.5$		2.0	2.0	ns	

## AC Characteristics (C<sub>L</sub> = 50 pF, R<sub>L</sub> = 500 $\Omega$ , input: t<sub>r</sub> = t<sub>f</sub> = 3 ns)

Characteristics	Symbol	Test Condition		-	Ta = 25°0	)	Ta = - 85	Unit	
			V <sub>CC</sub> (V)	Min	Тур.	Max	Min	Max	
Propagation delay time	t <sub>pLH</sub>	_	5.0 ± 0.5		7.2	10.5	1.0	12.0	ns
(CK-QA', QH')	tpHL								
Propagation delay time	t <sub>pHL</sub>		5.0 ± 0.5		6.0	10.0	1.0	11.5	ns
( CLR -QA', QH')									
Propagation delay time	t <sub>pLH</sub>	_	5.0 ± 0.5	_	7.4	11.4	1.0	13.0	ns
(CK-QA~QH)	t <sub>pHL</sub>						-		
Propagation delay time	t <sub>pHL</sub>	_	5.0 ± 0.5	_	6.3	10.5	1.0	12.0	ns
( CLR -QA~QH)									
Output enable time	t <sub>pZL</sub>	_	5.0 ± 0.5		7.4	11.4	1.0	13.0	ns
	t <sub>pZH</sub>								
Output disable time	t <sub>pLZ</sub>	_	5.0 ± 0.5		7.2	9.6	1.0	11.0	ns
	t <sub>pHZ</sub>		0.0 ± 0.0		1.2	0.0	1.0	11.0	110
Maximum clock frequency	f <sub>max</sub>	—	$5.0\pm0.5$	80	120		80	_	MHz
Input capacitance	C <sub>IN</sub>	_		_	5	10	_	10	pF
Bus input capacitance	C <sub>I/O</sub>	_		_	13				pF
Power dissipation	C <sub>PD</sub>								pF
capacitance	(Note)	—			100				μг

Note: C<sub>PD</sub> is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

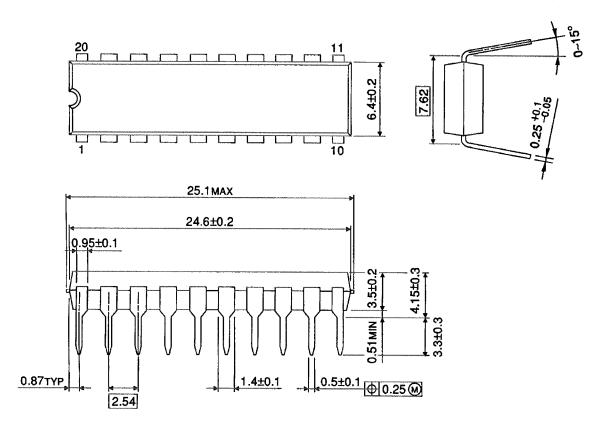
Average operating current can be obtained by the equation:

 $I_{CC}$  (opr) =  $C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}$ 

### Package Dimensions

DIP20-P-300-2.54A

Unit : mm



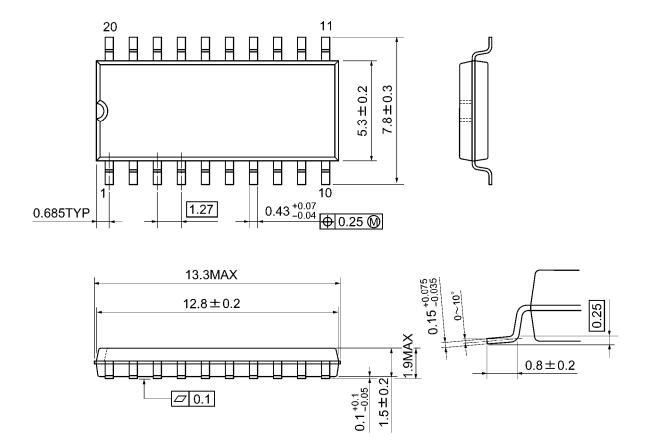
Weight: 1.30 g (typ.)



#### **Package Dimensions**

SOP20-P-300-1.27A

Unit: mm



Weight: 0.22 g (typ.)

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